

RELIABILITY REPORT



**RELIABILITY DATA
LT1032
8/21/2006**

• OPERATING LIFE TEST

| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE HOURS ⁽¹⁾ AT +125°C | NUMBER OF ⁽²⁾ FAILURES |
|--------------|-------------|------------------|------------------|---|-----------------------------------|
| CERDIP | 319 | 8512 | 9339 | 953.25 | 1 |
| PLASTIC DIP | 127 | 9025 | 9706 | 924.13 | 0 |
| | 446 | | | 1,877.39 | 1 |

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE HOURS | NUMBER OF FAILURES |
|---------------|-------------|------------------|------------------|----------------|--------------------|
| PLASTIC DIP | 700 | 9207 | 9849 | 20.40 | 0 |
| SOIC/SOT/MSOP | 1,413 | 9109 | 0047 | 78.66 | 1 |
| | 2,113 | | | 99.06 | 1 |

• TEMP CYCLE FROM -65°C to +150°C

| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE CYCLES | NUMBER OF FAILURES |
|---------------|-------------|------------------|------------------|-----------------|--------------------|
| CERDIP | 79 | 8512 | 8702 | 2.14 | 0 |
| PLASTIC DIP | 469 | 8644 | 0119 | 100.34 | 0 |
| SOIC/SOT/MSOP | 435 | 9109 | 0020 | 50.30 | 0 |
| | 983 | | | 152.77 | 0 |

• THERMAL SHOCK FROM -65°C to +150°C

| PACKAGE TYPE | SAMPLE SIZE | OLDEST DATE CODE | NEWEST DATE CODE | K DEVICE CYCLES | NUMBER OF FAILURES |
|---------------|-------------|------------------|------------------|-----------------|--------------------|
| CERDIP | 15 | 8702 | 8702 | 0.23 | 0 |
| PLASTIC DIP | 268 | 8644 | 9849 | 57.60 | 0 |
| SOIC/SOT/MSOP | 580 | 9109 | 0047 | 61.60 | 0 |
| | 863 | | | 119.43 | 0 |

(1) Assumes Activation Energy = 1.0 Electron Volts
 (2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 2.16 FITS
 (3) Mean Time Between Failures in Years = 52,813
 Note: 1 FIT = 1 Failure in One Billion Hours.